

FULLY INTEGRATED FIXED FREQUENCY LOW-JITTER, CRYSTAL-OSCILLATOR CLOCK GENERATOR

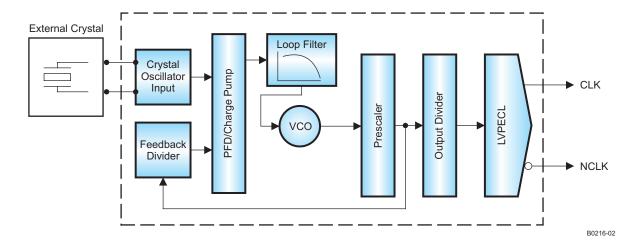
FEATURES

- Single 3.3 V Supply
- High-Performance Clock Generator, Incorporating Crystal Oscillator Circuitry With Integrated Frequency Synthesizer
- Low Output Jitter, as Low as 380 fs (rms integrated between 10 kHz–20 MHz)
- Low Phase Noise at 312.5 MHz, Less Than
 -120 dBc/Hz at 10 kHz and -147 dBc/Hz at 10
 MHz Offset From the Carrier
- Supports Crystal Frequencies or LVCMOS Input Frequencies at 31.25 MHz, 33.33 MHz, and 35.42 MHz

- Output Frequencies: 100 MHz, 106.25 MHz, 125 MHz, 156.25 MHz, 212.5 MHz, 250 MHz, and 312.5 MHz
- Differential Low-Voltage Positive Emitter Coupled Logic (LVPECL) Output
- Fully Integrated Voltage-Controlled Oscillator (VCO) Running from 1.75 GHz to 2.35 GHz
- Typical Power Consumption 300 mW
- Chip-Enable Control Pin
- QFN-24 Package
- ESD Protection Exceeds 2 kV HBM
- Industrial Temperature Range –40°C to 85°C

APPLICATIONS

Low-Cost, Low-Jitter Frequency Multiplier



DESCRIPTION

CDC421xxx is a high-performance, low-phase-noise clock generator. It has an integrated low-noise, LC-based voltage-controlled oscillator (VCO) that operates within the 1.75 GHz–2.35 GHz frequency range. It has an integrated crystal oscillator that operates in conjunction with an external AT-cut crystal to produce a stable frequency reference for the PLL-based frequency synthesizer. The output frequency (f_{out}) is proportional to the frequency of the input crystal (f_{xtal}).

The device operates in a 3.3 V supply environment and is characterized for operation from -40°C to 85°C.

CDC421xxx is available in a QFN-24 package.

A high-level block diagram of the CDC421xxx is shown in Figure 1.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



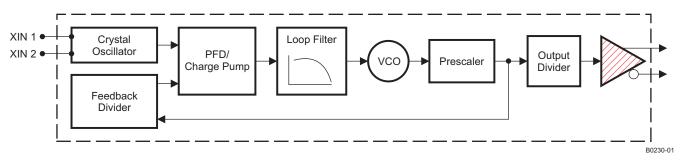


Figure 1. High-Level Block Diagram of the CDC421xxx

PACKAGE (QFN-24)

The CDC421xxx is packaged in a QFN-24 terminal package. The QFN package footprint is shown. Terminal locations and numbers are shown in Figure 2.

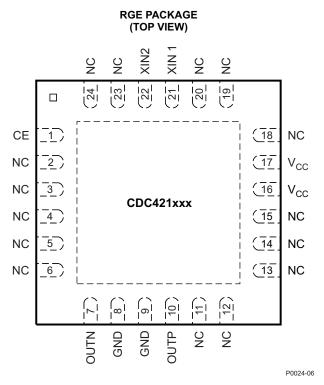


Figure 2. Pinout of the CDC421xxx QFN-24 Package

The terminal functions table shows the terminal descriptions for the CDC421xxx QFN-24 package.

Table 1. TERMINAL FUNCTIONS

TEF	RMINAL	TVDE	ESD	DESCRIPTION		
NAME	NO.	TYPE	PROTECTION	DESCRIPTION		
V _{CC}	16, 17	Power	Υ	3.3V power supply		
GND	8, 9	GND	Υ	Ground		
XIN 1 XIN 2	21 22	 	YZ	In crystal input mode, connect XIN1 to one end of the crystal and XIN2 to the other end of the crystal. In LVCMOS single-ended driven mode, XIN1 (pin 21) acts as input reference and XIN2 should connect to GND.		



TE	RMINAL	TYPE	ESD	DESCRIPTION	
NAME	NO.	ITPE	PROTECTION	DESCRIPTION	
CE	1	ı	Υ	Chip enable (LVCMOS input) CE = 1 enables the device and the outputs. CE = 0 disables all current sources (LVPECLP = LVPECLN = Hi-Z).	
OUTP	10	0	Υ	High-speed positive differential LVPECL output. (Outputs are enabled by CE)	
OUTN	7	0	Υ	High-speed negative differential LVPECL output. (Outputs are enabled by CE)	
NC	2–6, 11–15, 18–20, 23, 24	I or O	Υ	TI test pin. Do not connect; leave floating.	

DEVICE SELECTION

The CDC421xxx device is an LVPECL low-phase-noise clock generator designed to work with a low-frequency AT-crystal oscillator of a single-ended LVCMOS.

Table 2. Device Selection Table for CDC421xxx

С	DC421xxx		INDUT EDECUENCY OF	OUTPUT FREQUENCY FOR
DEVICE MARKING	ORDERING PART NUMBER	PACKAGE	INPUT FREQUENCY OR CRYSTAL VALUE (MHz)	THE SPECIFIED INPUT FREQUENCY (MHz)
421100	CDC421100RGER	QFN-24 tape and reel	33.3333	100.00
421100	CDC421100RGET	QFN-24 small tape and reel	33.3333	100.00
421106	CDC421106RGER	QFN-24 tape and reel	35.4167	106.25
421106	CDC421106RGET	QFN-24 small tape and reel	35.4167	106.25
421125	CDC421125RGER	QFN-24 tape and reel	31.2500	125.00
421125	CDC421125RGET	QFN-24 small tape and reel	31.2500	125.00
421156	CDC421156RGER	QFN-24 tape and reel	31.2500	156.25
421156	CDC421156RGET	QFN-24 small tape and reel	31.2500	156.25
421212	CDC421212RGER	QFN-24 tape and reel	35.4167	212.50
421212	CDC421212RGET	QFN-24 small tape and reel	35.4167	212.50
421250	CDC421250RGER	QFN-24 tape and reel	31.2500	250.00
421250	CDC421250RGET	QFN-24 small tape and reel	31.2500	250.00
421312	CDC421312RGER	QFN-24 tape and reel	31.2500	312.50
421312	CDC421312RGET	QFN-24 small tape and reel	31.2500	312.50

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

		VALUE	UNIT
V_{CC}	Supply voltage ⁽²⁾	-0.5 to 4.6	V
V_{I}	Voltage range for all other input pins ⁽²⁾	−0.5 to V _{CC} + 0.5	V
Io	Output current for LVPECL	-50	mA
	Electrostatic discharge (HBM)	2 k	V
T _A	Characterized free-air temperature range (no airflow)	-40 to 85	°C
TJ	Maximum junction temperature	125	°C
T _{stg}	Storage temperature range	-65 to 150	°C

⁽¹⁾ Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum rated conditions for extended periods may affect device reliability.

⁽²⁾ All voltage values are with respect to network ground terminal.



RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	3	3.3	3.6	V
T_A	Ambient temperature, no airflow, no heat sink	-40		85	Ô

ELECTRICAL CHARACTERISTICS

over recommended operating conditions for CDC421xxx device

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{CC}	Supply voltage		3	3.3	3.6	V
I _{VCC}	Total current at 3.3 V	3.3 V, 312.5 MHz		91	110	mA
LVPECL OU	TPUT		<u>.</u>			
f _{CLK}	Output frequency		100		312.5	MHz
V _{OH}	LVPECL high-level output voltage		V _{CC} - 1.20		V _{CC} - 0.81	V
V _{OL}	LVPECL low-level output voltage		V _{CC} – 2.17		V _{CC} – 1.36	V
V _{OD}	LVPECL differential output voltage		407		1076	mV
t _r	Output rise time	20% to 80% of V _{OUTpp}		170		ps
t _f	Output fall time	80% to 20% of V _{OUTpp}		170		ps
	Duty cycle of the output waveform		45%		55%	
LVCMOS INI	PUT		<u> </u>			
V _{IL,CMOS}	Low-level CMOS input voltage	V _{CC} = 3.3 V			0.3 V _{CC}	V
V _{IH,CMOS}	High-level CMOS input voltage	V _{CC} = 3.3 V	0.7 V _{CC}			V
I _{L,CMOS}	Low-level CMOS input current	$V_{CC} = V_{CC \text{ max}}, V_{IL} = 0 \text{ V}$			-200	μΑ
I _{H,CMOS}	High-level CMOS input current	$V_{CC} = V_{CC \text{ min}}, V_{IH} = 3.7 \text{ V}$			200	μА



JITTER CHARACTERISTICS IN INPUT CLOCK MODE

The jitter characterization test is performed using an LVCMOS input signal driving the CDC421xxx device.

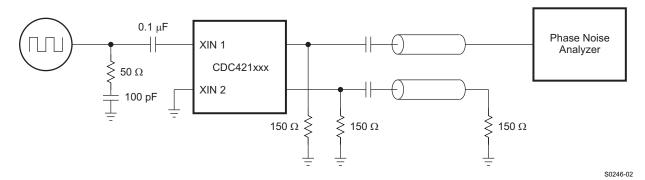


Figure 3. Jitter Test Configuration for an LVTTL Input Driving CDC421xxx

For the cases of the CDC421xxx being referenced by an external, clean LVCMOS input of 31.25 MHz, 33.33 MHz and 35.4167 MHz, the following tables list the measured SSB phase noise of all the outputs supported by the CDC421xxx device, (100 MHz, 106.25 MHz, 125 MHz, 156.25 MHz, 212.5 MHz, 250 MHz, and 312.5 MHz) from 100 Hz to 20 MHz from the carrier.

Table 3. Phase Noise Parameters With LVCMOS Input of 33.3333 MHz and LVPECL Output at 100.00 MHz

			-		
	PARAMETER	MIN	TYP	MAX	UNIT
Phase No	ise Specifications Under Following Conditions: f _{in} = 33.3333 MHz, f _{out} = 100.00 MHz				
phn ₁₀₀	Phase noise at 100 Hz		-111		dBc/Hz
phn _{1K}	Phase noise at 1 kHz		-121		dBc/Hz
phn _{10k}	Phase noise at 10 kHz		-131		dBc/Hz
phn _{100k}	Phase noise at 100 kHz		-133		dBc/Hz
phn _{1M}	Phase Noise at 1 MHz		-142		dBc/Hz
phn _{10M}	Phase noise at 10 MHz		-149		dBc/Hz
phn _{20M}	Phase noise at 20 MHz		-149		dBc/Hz
J _{RMS}	RMS jitter integrated from 12 kHz to 20 MHz		507		fs
Tj	Total jitter	;	35.33		ps
Dj	Deterministic jitter		11.54		ps

Table 4. Phase Noise Parameters With LVCMOS Input of 35.4167 MHz and LVPECL Output at 106.25 MHz

	PARAMETER	MIN TYP	MAX	UNIT
Phase No	ise Specifications Under Following Conditions: f _{in} = 35.4167 MHz , f _{out} = 106.25 MHz			
phn ₁₀₀	Phase noise at 100 Hz	-112		dBc/Hz
phn _{1K}	Phase noise at 1 kHz	-121		dBc/Hz
phn _{10k}	Phase noise at 10 kHz	-125		dBc/Hz
phn _{100k}	Phase noise at 100 kHz	-129		dBc/Hz
phn _{1M}	Phase noise at 1 MHz	-142		dBc/Hz
phn _{10M}	Phase noise at 10 MHz	-151		dBc/Hz
phn _{20M}	Phase noise at 20 MHz	-151		dBc/Hz
J_{RMS}	RMS jitter integrated from 12 kHz to 20 MHz	530		fs
Tj	Total jitter	30.39		ps
Dj	Deterministic jitter	11		ps



Table 5. Phase Noise Parameters With LVCMOS Input of 31.2500 MHz and LVPECL Output at 125.00 MHz

	PARAMETER	MIN TYP	MAX	UNIT
Phase Noi	se Specifications Under Following Conditions: f _{in} = 31.2500 MHz, f _{out} = 125.00 MHz			
phn ₁₀₀	Phase noise at 100 Hz	-108		dBc/Hz
phn _{1K}	Phase noise at 1 kHz	-118		dBc/Hz
phn _{10k}	Phase noise at 10 kHz	-127		dBc/Hz
phn _{100k}	Phase noise at 100 kHz	-130		dBc/Hz
phn _{1M}	Phase noise at 1 MHz	-139		dBc/Hz
phn _{10M}	Phase noise at 10 MHz	-147		dBc/Hz
phn _{20M}	Phase noise at 20 MHz	-147		dBc/Hz
J _{RMS}	RMS jitter integrated from 12 kHz to 20 MHz	529		fs
Tj	Total jitter	47.47		ps
Dj	Deterministic jitter	25.2		ps

Table 6. Phase Noise Parameters With LVCMOS Input of 31.2500 MHz and LVPECL Output at 156.25 MHz

	PARAMETER	MIN TYP	MAX	UNIT
Phase Noi	se Specifications Under Following Conditions: f _{in} = 31.2500 MHz, f _{out} = 156.25 MHz			
phn ₁₀₀	Phase noise at 100 Hz	-106		dBc/Hz
phn _{1K}	Phase noise at 1 kHz	-117		dBc/Hz
phn _{10k}	Phase noise at 10 kHz	-126		dBc/Hz
phn _{100k}	Phase noise at 100 kHz	-128		dBc/Hz
phn _{1M}	Phase noise at 1 MHz	-139		dBc/Hz
phn _{10M}	Phase noise at 10 MHz	-147		dBc/Hz
phn _{20M}	Phase noise at 20 MHz	-147		dBc/Hz
J _{RMS}	RMS jitter integrated from 12 kHz to 20 MHz	472		fs
Tj	Total jitter	31.54		ps
Dj	Deterministic jitter	9.12		ps

Table 7. Phase Noise Parameters With LVCMOS Input of 35.4167 MHz and LVPECL Output at 212.50 MHz

<u>.</u>	-		
PARAMETER	MIN TYP	MAX	UNIT
se Specifications Under Following Conditions: f _{in} = 35.4167 MHz, f _{out} = 212.50 MHz			
Phase noise at 100 Hz	-105		dBc/Hz
Phase noise at 1 kHz	-115		dBc/Hz
Phase noise at 10 kHz	-119		dBc/Hz
Phase noise at 100 kHz	-123		dBc/Hz
Phase noise at 1 MHz	-135		dBc/Hz
Phase noise at 10 MHz	-148		dBc/Hz
Phase noise at 20 MHz	-148		dBc/Hz
RMS jitter integrated from 12 kHz to 20 MHz	512		fs
Total jitter	33.96		ps
Deterministic jitter	13.78		ps
	se Specifications Under Following Conditions: f _{in} = 35.4167 MHz, f _{out} = 212.50 MHz Phase noise at 100 Hz Phase noise at 1 kHz Phase noise at 10 kHz Phase noise at 100 kHz Phase noise at 1 MHz Phase noise at 1 MHz Phase noise at 10 MHz Phase noise at 20 MHz RMS jitter integrated from 12 kHz to 20 MHz Total jitter	se Specifications Under Following Conditions: f _{in} = 35.4167 MHz, f _{out} = 212.50 MHz Phase noise at 100 Hz -105 Phase noise at 1 kHz -115 Phase noise at 10 kHz -119 Phase noise at 100 kHz -123 Phase noise at 1 MHz -135 Phase noise at 10 MHz -148 Phase noise at 20 MHz -148 RMS jitter integrated from 12 kHz to 20 MHz 512 Total jitter 33.96	se Specifications Under Following Conditions: f _{in} = 35.4167 MHz, f _{out} = 212.50 MHz Phase noise at 100 Hz -105 Phase noise at 1 kHz -115 Phase noise at 100 kHz -119 Phase noise at 1 MHz -123 Phase noise at 10 MHz -135 Phase noise at 20 MHz -148 RMS jitter integrated from 12 kHz to 20 MHz 512 Total jitter 33.96



Table 8. Phase Noise Parameters With LVCMOS Input of 31.2500 MHz and LVPECL Output at 250.00 MHz

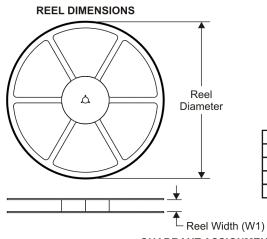
	PARAMETER	MIN	TYP	MAX	UNIT
Phase No	ise Specifications Under Following Conditions: f _{in} = 31.2500 MHz, f _{out} = 250.00 MHz				
phn ₁₀₀	Phase noise at 100 Hz		-103		dBc/Hz
phn _{1K}	Phase noise at 1 kHz		-112		dBc/Hz
phn _{10k}	Phase noise at 10 kHz		-121		dBc/Hz
phn _{100k}	Phase noise at 100 kHz		-124		dBc/Hz
phn _{1M}	Phase noise at 1 MHz		-134		dBc/Hz
phn _{10M}	Phase noise at 10 MHz		-148		dBc/Hz
phn _{20M}	Phase noise at 20 MHz		-149		dBc/Hz
J _{RMS}	RMS jitter integrated from 12 kHz to 20 MHz		420		fs
Tj	Total jitter	3	36.98		ps
Dj	Deterministic jitter	1	18.52		ps

Table 9. Phase Noise Parameters With LVCMOS Input of 31.2500 MHz and LVPECL Output at 312.50 MHz

	PARAMETER	MIN TYP	MAX	UNIT				
Phase No	Phase Noise Specifications Under Following Conditions: f _{in} = 31.2500 MHz, f _{out} = 312.50 MHz							
phn ₁₀₀	Phase noise at 100 Hz	-102		dBc/Hz				
phn _{1K}	Phase noise at 1 kHz	-111		dBc/Hz				
phn _{10k}	Phase noise at 10 kHz	-120		dBc/Hz				
phn _{100k}	Phase noise at 100 kHz	-123		dBc/Hz				
phn _{1M}	Phase noise at 1 MHz	-135		dBc/Hz				
phn _{10M}	Phase noise at 10 MHz	-147		dBc/Hz				
phn _{20M}	Phase noise at 20 MHz	-147		dBc/Hz				
J _{RMS}	RMS jitter integrated from 12 kHz to 20 MHz	378		fs				
Tj	Total jitter	29.82		ps				
Dj	Deterministic jitter	11		ps				



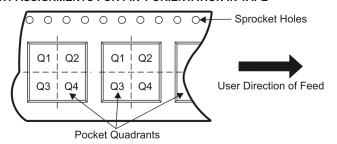
TAPE AND REEL INFORMATION



TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

	Α0	Dimension designed to accommodate the component width
Γ	B0	Dimension designed to accommodate the component length
	K0	Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
Г	D1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

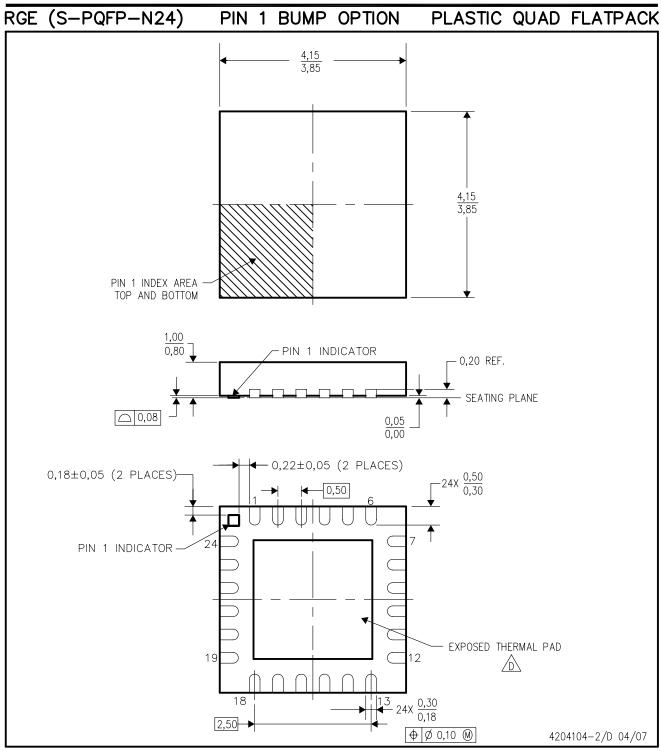
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDC421100RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421100RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421106RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421106RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421125RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421125RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421156RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421156RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421212RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421212RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421250RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421250RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421312RGER	VQFN	RGE	24	3000	330.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2
CDC421312RGET	VQFN	RGE	24	250	180.0	12.4	4.3	4.3	1.5	8.0	12.0	Q2





*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDC421100RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421100RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421106RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421106RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421125RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421125RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421156RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421156RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421212RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421212RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421250RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421250RGET	VQFN	RGE	24	250	190.5	212.7	31.8
CDC421312RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
CDC421312RGET	VQFN	RGE	24	250	190.5	212.7	31.8



- NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
 - B. This drawing is subject to change without notice.
 - C. Quad Flatpack, No-Leads (QFN) package configuration.
 - The package thermal pad must be soldered to the board for thermal and mechanical performance.
 - See the Product Data Sheet for details regarding the exposed thermal pad dimensions.
 - E. Falls within JEDEC MO-220.



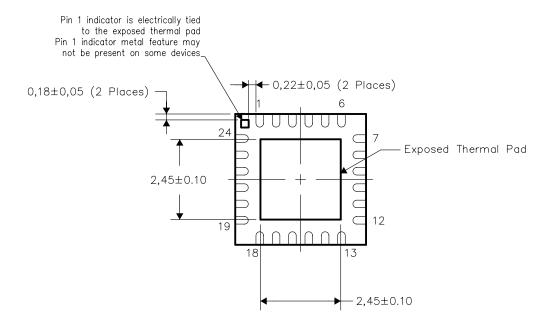


THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No—Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

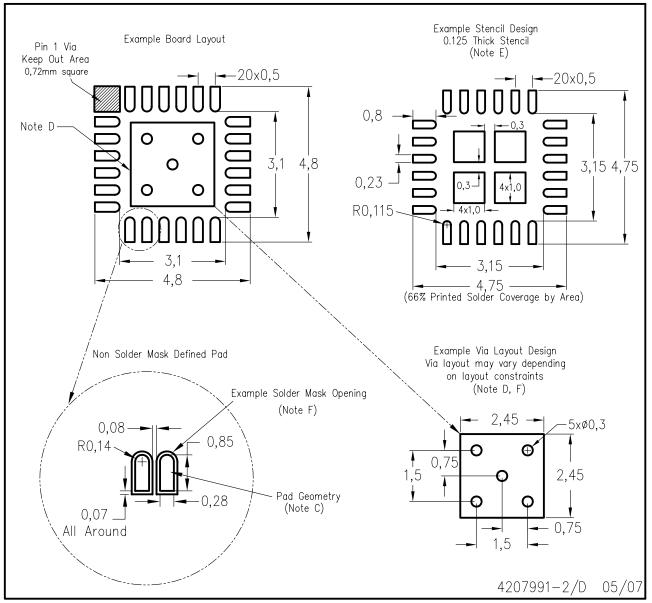


Bottom View

NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

RGE (S-PQFP-N24)



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



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